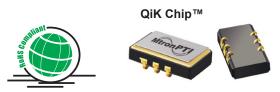


Product Features

- Featuring *QiK Chip*[™] Technology
- Superior Jitter Performance (comparable to SAW based)
- APR of ±50 or ±100ppm over industrial temperature range
- Frequencies from 150 MHz to 1.4 GHz
- Designed for a short 2 week cycle time



Product Description

The M320x series of VCXO's is designed with a hermetically sealed high precision AT cut quartz crystal, combined with our QiK Chip[™] technology. This combination provides an industry setting 0.35 ps RMS jitter performance and excellent Phase Noise for your demanding circuit. The M310x is available in LVPECL, LVDS, or CML output and can be built to a variety of power requirements, 3.3, 2.5, and 1.8V. Tight thermal stability performance, broad frequency range, an industry standard 9x14mm package, and the ability to build and provide product in approximately 2 weeks, gives the designer a quick, solid foundation to build a solution with.

Product Applications

- Telecommunications such as SONET / SDH / DWDM / FEC / SERDES / OC-3 thru OC-192
- Wireless base stations / WLAN / Gigabit Ethernet
- xDSL, Network Communications

- Avionic Flight Controls
- Military Communications
- Clock and Data Recovery
- Low Jitter Clock Generation

Product Ordering Information

	M3200	6	А	G	Р	J	00.0000 MHz
Product Series							
M3200 = 3.3 V							
M3201 = 2.5 V							
M3202 = 1.8 V							
Temperature Rang	je						
1: 0 ℃ to +70 ℃							
6: -20 ℃ to +70 ℃							
2: -40 ℃ to +85 ℃							
Absolute Pull Ran	ge (APR)						
A : ±50 ppm	B : ±100 ppm	D : ±200	opm				
Enable/Disable Fu	nction						
G: Enable High (Pir	1 2)						
M: Enable Low (Pin	12)						
U: No Enable/Disat	ble Function						
Output Waveform	n						
P: LVPECL	L: LVDS	M: CML		C: CMOS	6		
Package/Lead Cor	figurations					-	
J: 9x14 mm (J-lead)						
Frequency (custor	ner specified)						-

M3200Sxxx, M3201Sxxx & M3202Sxxx - Custom datasheets.



Performance Characteristics

	PARAMETER	Symbol	Min.	Тур.	Max.	Units	Condition/Notes		
	Frequency Range	F	50		1400	MHz	See Note 1		
	Operating Temperature	TA	(\$	See orderii	ng informatior	ו)			
	Storage Temperature	Ts	-55		+125	°C			
	Frequency Stability	$\Delta F/F$		±25		ppm			
	Aging 1st Year Thereafter (per year)		-3 -1		+3 +1	ppm ppm			
	Pullability/APR		(\$	See orderii	ng information	1)	See Note 2		
	Gain Transfer Function			90 135 180		ppm/V ppm/V ppm/V	For ±50 ppm APR For ±100 ppm APR For ±200 ppm APR		
	Control Voltage	Vc	0.18 0.25 0.30	0.90 1.25 1.65	1.62 2.25 3.0	> > > >	@ 1.8V Vcc @ 2.5V Vcc @ 3.3V Vcc		
	Linearity			1	5	%	Positive Monotonic		
	Modulation Bandwidth	fm	10			KHz	-3 dB bandwidth		
	Input Impedance	Zin	500k	1M	1.00	Ohms	@ DC		
suo	Supply Voltage	Vcc	1.71 2.375 3.135	1.8 2.5 3.3	1.89 2.625 3.465	>>>	LVDS/CML		
ficati	Input Current	lcc			125 90	mA mA	LVPECL/LVDS/CML CMOS		
Electrical Specifications	Load			100 Ohm d	o (Vcc –2) Vd ifferential load 5 pF		See Note 3 LVPECL Waveform LVDS/CML Waveform CMOS Waveform LVPECL: Vdd-1.3 V		
Elec	Symmetry (Duty Cycle)		45		55	%	LVDS: 1.25 V CMOS: 50% Vdd		
	Output Skew			20 15 20		ps ps ps	LVPECL CML LVDS		
	Differential Voltage	Vod	250	350	450	mV	LVDS		
		Vod	0.7	0.95	1.20	Vpp	CML		
	Common Mode Output Voltage	Vcm		1.2		V	LVDS		
	Logic "1" Level	Voh	Vcc -1.02 90			V % Vdd	LVPECL CMOS		
	Logic "0" Level	Vol			Vcc -1.63 10	V % Vdd	LVPECL CMOS		
	Rise/Fall Time	Tr/Tf		0.23	0.35	ns	@ 20/80% LVPECL, LVDS, CML		
	Enable Function		0.5V r 0.5V	nax: Outpu V max or N	N/C: Output it disables to I/C: Output ac	Output Option G Output Option M			
	Start up Time		00% VC		put disables t	o nign-Z ms			
	Phase Jitter				10	1115			
	@ 622.08 MHz	φJ		0.25		ps RMS	Integrated 12 kHz – 20 MHz		
a l	Mechanical Shock	I)-202 Mot	and 213 Con	dition C			
Environmental	Vibration	Per MIL-STD-202, Method 213, Condition C Per MIL-STD-202, Method 201 & 204							
Ē	Max Soldering Conditions		See solder profile, Figure 1						
iro	Hermeticity		Per MIL-STD-202, Method 112 (1 x 10 ⁻⁸ atm cc/s of helium)						
l S	Solderability		Per MIL-STD-883, Method 203						
1									

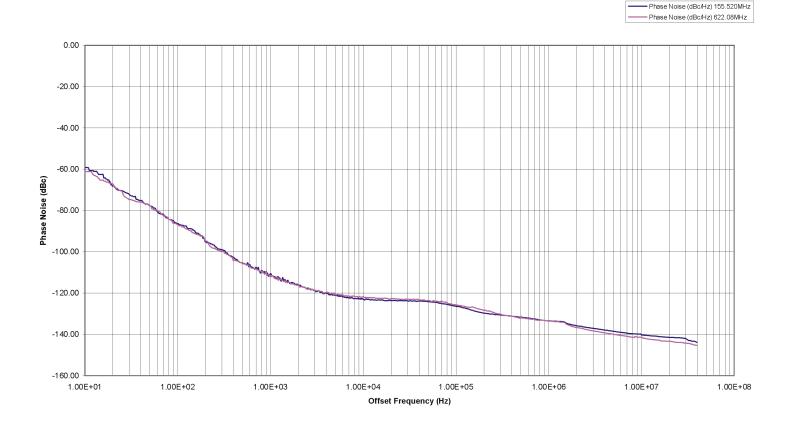
Note 1: Contact factory for standard frequency availability over 945 MHz.

Note 2: APR specification is inclusive of initial tolerance, deviation over temperature, shock, vibration, supply voltage, and aging for one year at 50°C mean ambient temperature.

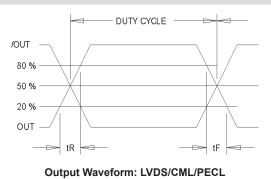
Note 3: See Load Circuit Diagram in this Datasheet. Consult factory with nonstandard output load requirements.



Phase Noise Plot

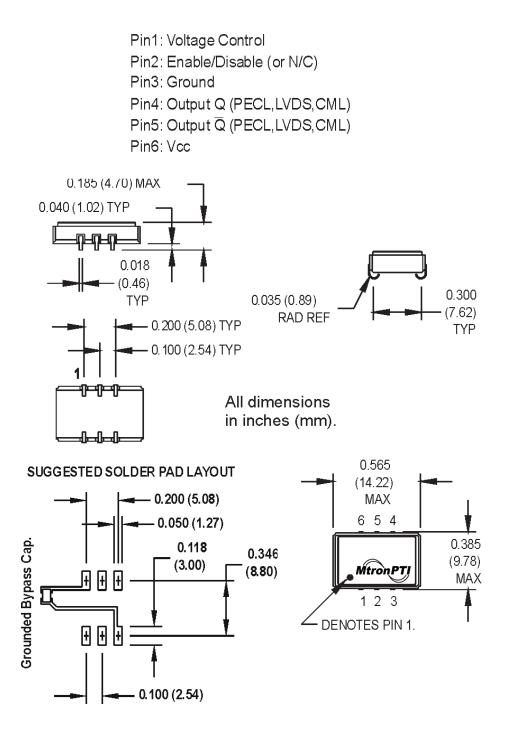


Output Waveform





Product Dimension & Pinout Information





Handling Information

Although protection circuitry has been designed into the M320x oscillator, proper precautions should be taken to avoid exposure to electrostatic discharge (ESD) during handling and mounting. MtronPTI utilizes a human-body model (HBM) and a charged-device model (CDM) for ESD-susceptibility testing and protection design evaluation. ESD voltage thresholds are dependent on the circuit parameters used to define the mode. Although no industry-wide standard has been adopted for the CDM, a standard HBM (resistance = 1500 Ω , capacitance = 100 pF) is widely used and therefore can be used for comparison purposes. The HBM ESD threshold presented here was obtained using these circuit parameters.

Model	ESD Threshold, Minimum	Unit		
Human Body	1500*	V		
Charged Device	1500*	V		

* MIL-STD-833D, Method 3015, Class 1

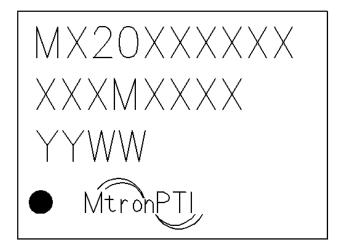


Quality Parameters

Environmental Specifications/Qualification Testing Performed on the M320 VCXO								
Test	Test Method	Test Condition						
Electrical Characteristics	Internal Specification	Per Specification						
Frequency vs. Temperature	Internal Specification	Per Specification						
Mechanical Shock	MIL-STD-202, Method 213, C	100 g's						
Vibration	MIL-STD-202, Method 201-204	10 g's from 10-2000 Hz						
Thermal Cycle	MIL-STD-883, Method 1010, B	-55 Deg. C to +125 Deg. C, 15 minute Dwell, 10 cycles						
Aging	Internal Specification	168 Hours at 105 Degrees C						
Gross Leak	MIL-STD-202, Method 112	30 Second Immersion						
Fine Leak	MIL-STD-202, Method 112	Must meet 1x10 ⁻⁸						
Solderability	MIL-STD-883, Method 2003	8 Hour Steam Age – Must Exhibit 95% coverage						
Resistance to Solvents	MIL-STD-883, Method 2015	Three 1 minute soaks						
Terminal Pull	MIL-STD-883, Method 2004, A	2 Pounds						
Lead Bend	MIL-STD-883, Method 2004, B1	1 Bending Cycle						
Physical Dimensions	MIL-STD-883, Method 2016	Per Specification						
Internal Visual	Internal Specification	Per Internal Specification						

Part Marking Guide

- Line 1: Model Number
- Line 2: Frequency
- Line 3: Date Code
- Line 4: Pin 1 Indicator / MtronPTI



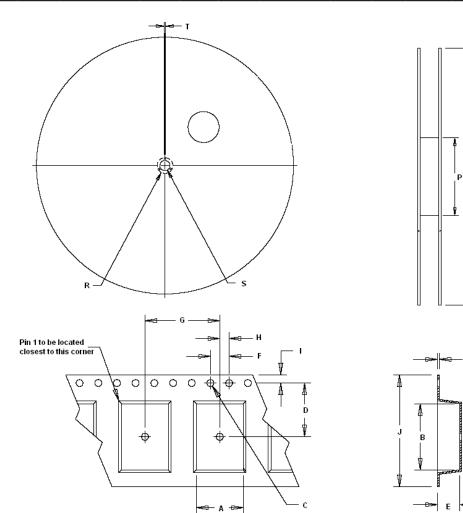


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Т

Tape & Reel Specifications

(all measurements are in mm)	Α	В	С	D	Е	F	G	н	Ι	J	L	Р	Q	R	S	т
M320x	10.00	14.20	1.50	11.50	4.85	4.00	16.00	2.00	1.75	24.00	0.35	100.00	330.00	20.20	13.00	2.00



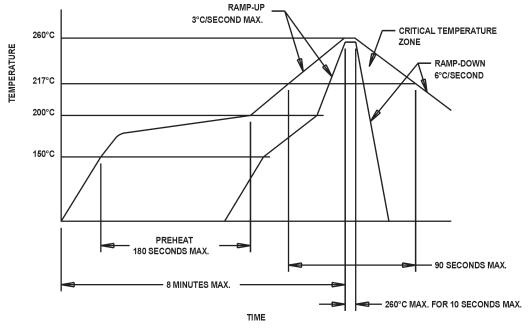
Standard Tape and Reel: 500 parts per reel

Product Revision Table

Date	Revision	PCN Number	Details of Revision
7/20/07	А	10118	IC Revision to improve phase noise and electrical performance



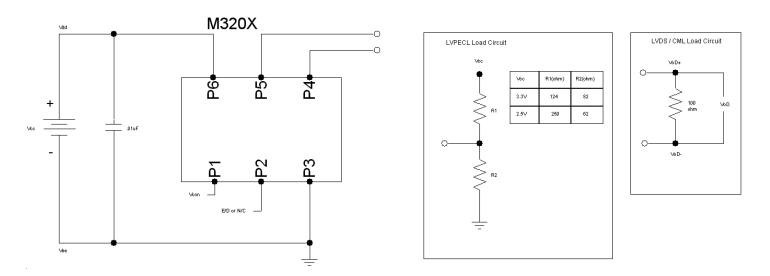
Maximum Soldering Conditions



Solder Conditions

Note: Exceeding these limits may damage the device.

Typical Test Circuit & Load Circuit Diagrams



For custom products or additional specifications contact our sales team at 800.762.8800 (toll free) or 605.665.9321

For more information on this product visit the MtronPTI website at www.mtronpti.com